74HC3G07; 74HCT3G07

Triple buffer with open-drain outputs Rev. 02 — 12 May 2009

Product data sheet

General description 1.

The 74HC3G07 and 74HCT3G07 are high-speed Si-gate CMOS devices. They provide three buffers with open-drain outputs.

The outputs of the 74HC3G07 and 74HCT3G07 devices are open drains and can be connected to other open-drain outputs to implement active-LOW wired-OR or active-HIGH wired-AND functions. For digital operation this device must have a pull-up resistor to establish a logic HIGH-level.

The HC device has CMOS input switching levels and supply voltage range 2 V to 6 V.

The HCT device has TTL input switching levels and supply voltage range 4.5 V to 5.5 V.

2. **Features**

- Wide supply voltage range from 2.0 V to 6.0 V
- High noise immunity
- Low power dissipation
- Multiple package options
- ESD protection:
 - ◆ HBM JESD22-A114E exceeds 2000 V
 - ◆ MM JESD22-A115-A exceeds 200 V
- Specified from -40 °C to +85 °C and -40 °C to +125 °C

Ordering information 3.

Table 1. **Ordering information**

Type number	Package							
	Temperature range	Name	Description	Version				
74HC3G07DP	-40 °C to +125 °C TSSOP		plastic thin shrink small outline package; 8 leads;	SOT505-2				
74HCT3G07DP			body width 3 mm; lead length 0.5 mm					
74HC3G07DC	$-40~^{\circ}\text{C}$ to +125 $^{\circ}\text{C}$	VSSOP8	plastic very thin shrink small outline package; 8 leads;	SOT765-1				
74HCT3G07DC			body width 2.3 mm					
74HC3G07GD	$-40~^{\circ}\text{C}$ to +125 $^{\circ}\text{C}$	XSON8U	plastic extremely thin small outline package; no leads;	SOT996-2				
74HCT3G07GD			8 terminals; UTLP based; body $3 \times 2 \times 0.5$ mm					

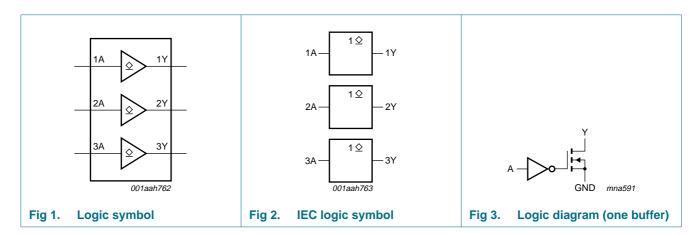


4. Marking

Table 2. Marking code

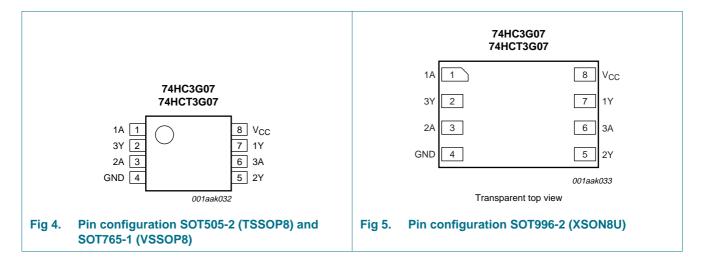
Type number	Marking code
74HC3G07DP	H07
74HCT3G07DP	T07
74HC3G07DC	H07
74HCT3G07DC	T07
74HC3G07GD	H07
74HCT3G07GD	T07

5. Functional diagram



6. Pinning information

6.1 Pinning



6.2 Pin description

Table 3. Pin description

Symbol	Pin	Description
1A, 2A, 3A	1, 3, 6	data input
GND	4	ground (0 V)
1Y, 2Y, 3Y	7, 5, 2	data output
V_{CC}	8	supply voltage

7. Functional description

Table 4. Function table[1]

Input nA	Output nY
L	L
Н	Z

^[1] H = HIGH voltage level; L = LOW voltage level; Z = high-impedance OFF-state.

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	- m	mA mA
$\begin{array}{cccccccccccccccccccccccccccccccccccc$	- m	mA
V_{O} output voltage		
high-impedance mode		
I_{O} output current $V_{O} = -0.5 \text{ V to } 7.0 \text{ V}$	$V_{CC} + 0.5 V$	V
	7.0 V	V
I _{CC} supply current [1] - 50	· m	mΑ
	50 m	mΑ
I _{GND} ground current [1] -50 -	· m	mΑ
T_{stg} storage temperature -65 +	+150 °(°C
P_D dynamic power dissipation $T_{amb} = -40 ^{\circ}\text{C}$ to +125 $^{\circ}\text{C}$ $\boxed{2}$ - 30		mW

^[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

^[2] For TSSOP8 package: above 55 °C the value of P_{tot} derates linearly with 2.5 mW/K. For VSSOP8 package: above 110 °C the value of P_{tot} derates linearly with 8 mW/K. For XSON8U package: above 118 °C the value of P_{tot} derates linearly with 7.8 mW/K.

9. Recommended operating conditions

Table 6. Recommended operating conditions

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	74HC3G07			74HCT3G07			Unit
			Min	Тур	Max	Min	Тур	Max	
V_{CC}	supply voltage		2.0	5.0	6.0	4.5	5.0	5.5	V
VI	input voltage		0	-	6.0	0	-	5.5	V
Vo	output voltage		0	-	V_{CC}	0	-	V_{CC}	V
T _{amb}	ambient temperature		-40	+25	+125	-40	+25	+125	°C
$\Delta t/\Delta V$	input transition rise and fall rate	$V_{CC} = 2.0 \text{ V}$	-	-	625	-	-	-	ns/V
		$V_{CC} = 4.5 \text{ V}$	-	1.67	139	-	1.67	139	ns/V
		$V_{CC} = 6.0 \text{ V}$	-	-	83	-	-	-	ns/V

10. Static characteristics

Table 7. Static characteristics

Voltages are referenced to GND (ground = 0 V). All typical values are measured at T_{amb} = 25 °C.

Symbol	Parameter	Conditions	-40) °C to +8	5 °C	-40 °C to +125 °C		Unit
			Min	Typ[1]	Max	Min	Max	
74HC3G	07							
V_{IH}	HIGH-level input	V _{CC} = 2.0 V	1.5	1.2	-	1.5	-	V
	voltage	V _{CC} = 4.5 V	3.15	2.4	-	3.15	-	V
		V _{CC} = 6.0 V	4.2	3.2	-	4.2	-	V
V_{IL}	LOW-level input	V _{CC} = 2.0 V	-	0.8	0.5	-	0.5	V
	voltage	V _{CC} = 4.5 V	-	2.1	1.35	-	1.35	V
		V _{CC} = 6.0 V	-	2.8	1.8	-	1.8	V
V_{OL}	LOW-level output voltage	$V_I = V_{IH}$ or V_{IL}						
		$I_O = 20 \mu A; V_{CC} = 2.0 \text{ V}$	-	0	0.1	-	0.1	V
		$I_O = 20 \mu A; V_{CC} = 4.5 V$	-	0	0.1	-	0.1	V
		$I_O = 20 \mu A; V_{CC} = 6.0 \text{ V}$	-	0	0.1	-	0.1	V
		$I_{O} = 4.0 \text{ mA}; V_{CC} = 4.5 \text{ V}$	-	0.15	0.33	-	0.4	V
		$I_{O} = 5.2 \text{ mA}; V_{CC} = 6.0 \text{ V}$	-	0.16	0.33	-	0.4	V
II	input leakage current	$V_I = V_{CC}$ or GND; $V_{CC} = 6.0 \text{ V}$	-	-	±0.1	-	±1.0	μΑ
I _{LO}	output leakage current	$V_I = V_{IH}$; $V_O = V_{CC}$ or GND	-	-	±5.0	-	±10	μА
I _{CC}	supply current	per input pin; $V_{CC} = 6.0 \text{ V}$; $V_I = V_{CC}$ or GND; $I_O = 0 \text{ A}$;	-	-	10	-	20	μА
Cı	input capacitance		-	1.5	-	-	-	pF

 Table 7.
 Static characteristics ...continued

Voltages are referenced to GND (ground = 0 V). All typical values are measured at T_{amb} = 25 °C.

Symbol	Parameter	Conditions	-40	0 °C to +8	5 °C	–40 °C t	o +125 °C	Unit
			Min	Typ[1]	Max	Min	Max	
74HCT3	G07							'
V _{IH}	HIGH-level input voltage	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	2.0	1.6	-	2.0	-	V
V_{IL}	LOW-level input voltage	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	-	1.2	8.0	-	0.8	V
V _{OL}	LOW-level output voltage	$V_I = V_{IH}$ or V_{IL}						
		$I_O = 20 \mu A$; $V_{CC} = 4.5 \text{ V}$	-	0	0.1	-	0.1	V
		$I_{O} = 4.0 \text{ mA}; V_{CC} = 4.5 \text{ V}$	-	0.15	0.33	-	0.4	V
I _I	input leakage current	$V_I = V_{CC}$ or GND; $V_{CC} = 5.5 \text{ V}$	-	-	±1.0	-	±1.0	μΑ
I _{LO}	output leakage current	$V_I = V_{IH}$; $V_O = V_{CC}$ or GND	-	-	±5.0	-	±10	μΑ
I _{CC}	supply current	per input pin; $V_{CC} = 5.5 \text{ V}$; $V_I = V_{CC}$ or GND; $I_O = 0 \text{ A}$;	-	-	10	-	20	μΑ
ΔI_{CC}	additional supply current	per input; $V_{CC} = 4.5 \text{ V to } 5.5 \text{ V};$ $V_I = V_{CC} - 2.1 \text{ V};$ $I_O = 0 \text{ A}$	-	-	375	-	410	μΑ
Cı	input capacitance		-	1.5	-	-	-	рF

^[1] Typical values are measured at T_{amb} = 25 °C.

11. Dynamic characteristics

Table 8. Dynamic characteristics

Voltages are referenced to GND (ground = 0 V); all typical values are measured at T_{amb} = 25 °C; for test circuit see <u>Figure 7</u>.

Symbol	Parameter	Conditions		–40 °C to +85 °C		–40 °C to +125 °C		Unit	
				Min	Тур	Max	Min	Max	
74HC3G	07								
t _{PZL}	OFF-state to LOW	nA to nY; see Figure 6							
	propagation delay	$V_{CC} = 2.0 \text{ V}$		-	25	95	-	125	ns
		$V_{CC} = 4.5 V$		-	9	19	-	25	ns
		$V_{CC} = 6.0 \text{ V}$		-	7	16	-	20	ns
t_{PLZ}	LOW to OFF-state propagation delay	nA to nY; see Figure 6							
		$V_{CC} = 2.0 \text{ V}$		-	25	95	-	125	ns
		$V_{CC} = 4.5 V$		-	11	23	-	30	ns
		$V_{CC} = 6.0 \text{ V}$		-	10	23	-	26	ns
t_{THL}	HIGH to LOW output	nY; see Figure 6							
	transition time	$V_{CC} = 2.0 \text{ V}$		-	18	95	-	125	ns
		$V_{CC} = 4.5 V$		-	6	19	-	25	ns
		$V_{CC} = 6.0 \text{ V}$		-	5	16	-	20	ns
C_{PD}	power dissipation capacitance	$V_I = GND \text{ to } V_{CC}$	[1]	-	4	-	-	-	pF

 Table 8.
 Dynamic characteristics ...continued

Voltages are referenced to GND (ground = 0 V); all typical values are measured at T_{amb} = 25 °C; for test circuit see Figure 7.

Symbol	Parameter	Conditions	Conditions –40 °C to +85 °C		–40 °C to +125 °C		Unit	
			Min	Тур	Max	Min	Max	
74HCT3	G07		'			•		
t _{PZL}	OFF-state to LOW propagation delay	nA to nY; see Figure 6						
		V _{CC} = 4.5 V	-	11	27	-	32	ns
t _{PLZ}	LOW to OFF-state propagation delay	nA to nY; see Figure 6						
		V _{CC} = 4.5 V	-	10	26	-	31	ns
t _{THL}	HIGH to LOW output transition time	V _{CC} = 4.5 V; see <u>Figure 6</u>	-	6	19	-	22	ns
C_{PD}	power dissipation capacitance	$V_I = GND \text{ to } V_{CC} - 1.5 \text{ V}$	<u>[1]</u> _	4		-	-	pF

[1] C_{PD} is used to determine the dynamic power dissipation (P_D in μW).

 $P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma (C_L \times V_{CC}^2 \times f_o)$ where:

 f_i = input frequency in MHz;

fo = output frequency in MHz;

C_L = output load capacitance in pF;

V_{CC} = supply voltage in V;

N = number of inputs switching;

 $\Sigma(C_L \times V_{CC}^2 \times f_0)$ = sum of outputs.

12. Waveforms

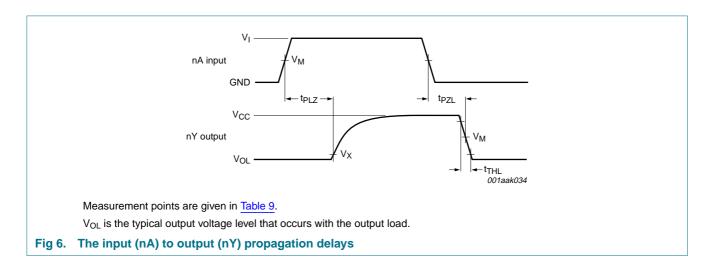
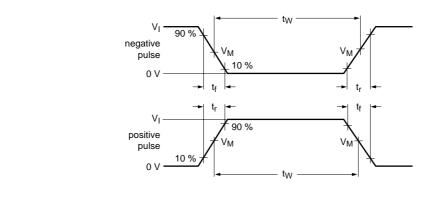
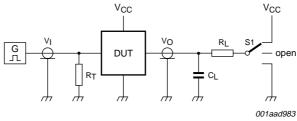


Table 9. Measurement points

Туре	Input	Output			
	V _M	V _M	V _X		
74HC3G07	$0.5 \times V_{CC}$	$0.5 \times V_{CC}$	$0.1 \times V_{CC}$		
74HCT3G07	1.3 V	1.3 V	$0.1 \times V_{CC}$		





Test data is given in Table 10.

Definitions for test circuit:

 R_T = Termination resistance should be equal to output impedance Z_0 of the pulse generator.

 C_L = Load capacitance including jig and probe capacitance.

R_I = Load resistance.

S1 = Test selection switch.

Fig 7. Test circuit for measuring switching times

Table 10. Test data

Туре	Input		Load	S1 position	
	VI	t _r , t _f	CL	R _L	t _{PZL} , t _{PLZ}
74HC3G07	GND to V _{CC}	≤ 6 ns	50 pF	1 kΩ	V _{CC}
74HCT3G07	GND to 3 V	≤ 6 ns	50 pF	1 kΩ	V _{CC}

13. Package outline

TSSOP8: plastic thin shrink small outline package; 8 leads; body width 3 mm; lead length 0.5 mm SOT505-2

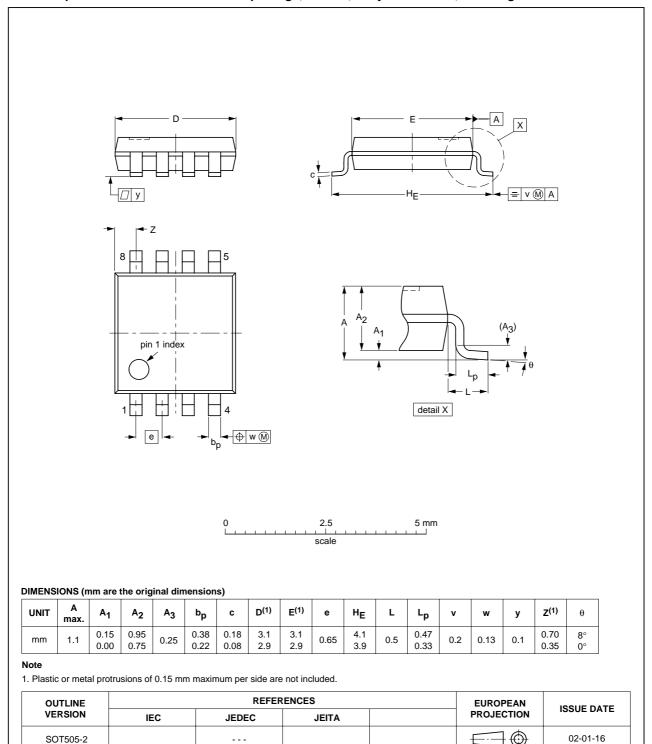
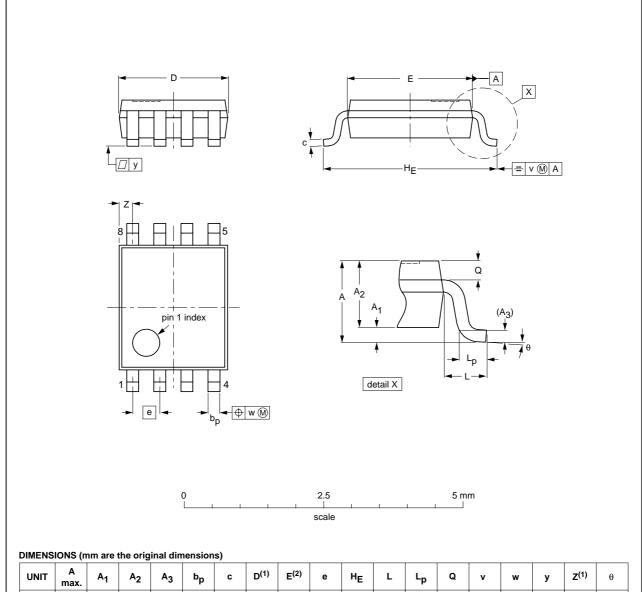


Fig 8. Package outline SOT505-2 (TSSOP8)

VSSOP8: plastic very thin shrink small outline package; 8 leads; body width 2.3 mm

SOT765-1



U	INIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽²⁾	е	HE	L	Lp	Q	v	w	у	Z ⁽¹⁾	θ
r	mm	1	0.15 0.00	0.85 0.60	0.12	0.27 0.17	0.23 0.08	2.1 1.9	2.4 2.2	0.5	3.2 3.0	0.4	0.40 0.15	0.21 0.19	0.2	0.13	0.1	0.4 0.1	8° 0°

Notes

- 1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- 2. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE				
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE		
SOT765-1		MO-187				02-06-07		

Fig 9. Package outline SOT765-1 (VSSOP8)

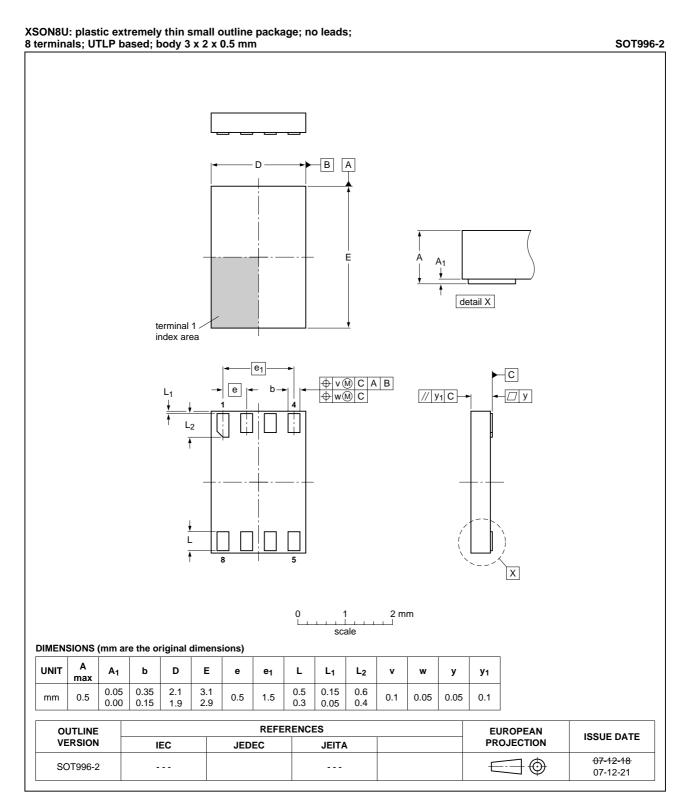


Fig 10. Package outline SOT996-2 (XSON8U)

14. Abbreviations

Table 11. Abbreviations

Acronym	Description
CMOS	Complementary Metal Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
HBM	Human Body Model
MM	Machine Model
TTL	Transistor-Transistor Logic

15. Revision history

Table 12. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74HC_HCT3G07_2	20090512	Product data sheet	-	74HC_HCT3G07_1
Modifications:		of this data sheet has been re f NXP Semiconductors.	designed to comply v	vith the new identity
	 Legal texts h 	nave been adapted to the new	company name whe	re appropriate.
	 Added type 	number 74HC3G07GD and 7	4HCT3G07GD (XSO	N8U package)
74HC_HCT3G07_1	20031015	Product specification	-	-

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16.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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